



Metrics NA TC Chapter

Thursday, November 9, 2023

1:30-5:30 PM Pacific

AGENDA

	Time
Welcome/Call to Order	1:30-1:45
1.1 Introductions	
1.2 Required Meeting Elements (Membership Requirements, Antitrust and Intellectual Property Reminders, and Effective Meeting Guidelines)	
1.3 Agenda Review	

Review of Previous Meeting Minutes (including open Action Items review)	1:45-2:00
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Staff Report	2:00-2:15
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Liaison Reports	2:15-2:30
1.4 Japan TC Chapter	

Ballot Review (including safety and IP checks)	2:30-4:00
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#	When	TF	Details
6931	Cycle 7-2023	CCC TF	New Standard: Test Method for Measuring Organics Contamination Through Thermal Desorption or Solvent Extraction Gas Chromatography Mass Spectrometry of Critical Chamber Components Used in Semiconductor Wafer Processing and Inspection
7129	Cycle 7-2023	CCC TF	New Standard: Test Method for Measuring Particles and Contamination by A Liquid Particle Counter of Critical Chamber Components Used in Semiconductor Wafer Processing and Inspection
7130	Cycle 7-2023	CCC TF	New Standard: Test Method for Measuring Surface Contamination by Particle Concentration Through Replacement Substrate and Optical Metrology of Critical Chamber Components Used in Semiconductor Wafer Processing and Inspection
7131	Cycle 7-2023	RF Measurements TF	Reapproval of SEMI E135-0918, Test Method for RF Generators to Determine Transient Response for RF Power Delivery Systems Used in Semiconductor Processing Equipment
7132	Cycle 7-2023	RF Measurements TF	Reapproval of SEMI E143-0306 (Reapproved 0518), Test Method for Measuring Power and Variation into a 50-Ω Load and Power Variation and Spectrum into a Load with a VSWR of 2.0 at any phase Angle



Subcommittee & Task Force Reports

- 1.5 ESD/ESC Task Force – Chuck McClain **4:00-4:30**
- 1.6 EMC Task Force – Vladimir Kraz / Mark Frankfurth
- 1.7 RF Measurements Task Force – Supika Mashiro
- 1.8 Equipment RAMP Metrics Task Force – Paul Schneider / Todor Ganev
- 1.9 Critical Chamber Components (CCC) Test Methods Task Force – Michael Cox / Supika Mashiro
- 1.10 License Server Certification TF – Sashi Subramanian

7 Old Business 4:30-4:45

- 1.11 Standards due for Five-Year Review
- 1.12 SNARFs approaching Three-Year Document Development Project Period

8 New Business 4:45-5:00

- 1.13 New TFOFs & SNARFs
- 1.14 New Ballot(s) Submission Summary
- 1.15 IEC Liaison

9 New Action Item Review 5:00-5:20

10 Next Meetings Schedule (TBD) 5:20-5:30

Date/Time/Location

- ESD/ESC Task Force
- EMC Task Force
- RF Measurements Task Force
- Equipment RAMP Metrics Task Force
- Critical Chamber Components (CCC) Test Methods Task Force
- License Server Certification Task Force

11 Adjournment 5:30

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